DO NOT ENTER: /C.C./

11/08/2010

DOCKET NO: 287800US26PCT

## IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF

:

MASAYUKI OIKAWA, ET AL.

: EXAMINER: CHAN, CEDRIC A.

SERIAL NO: 10/574,286

:

FILED: MARCH 31, 2006

: GROUP ART UNIT: 1797

FOR: INSPECTION METHOD AND INSPECTION ASSISTING DEVICE FOR QUARTZ PRODUCT OF

SEMICONDUCTOR PROCESSING

**APPARATUS** 

## **AMENDMENT**

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Office Action dated September 2, 2010, please amend the aboveidentified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 9 of this paper.